

FIG. 1

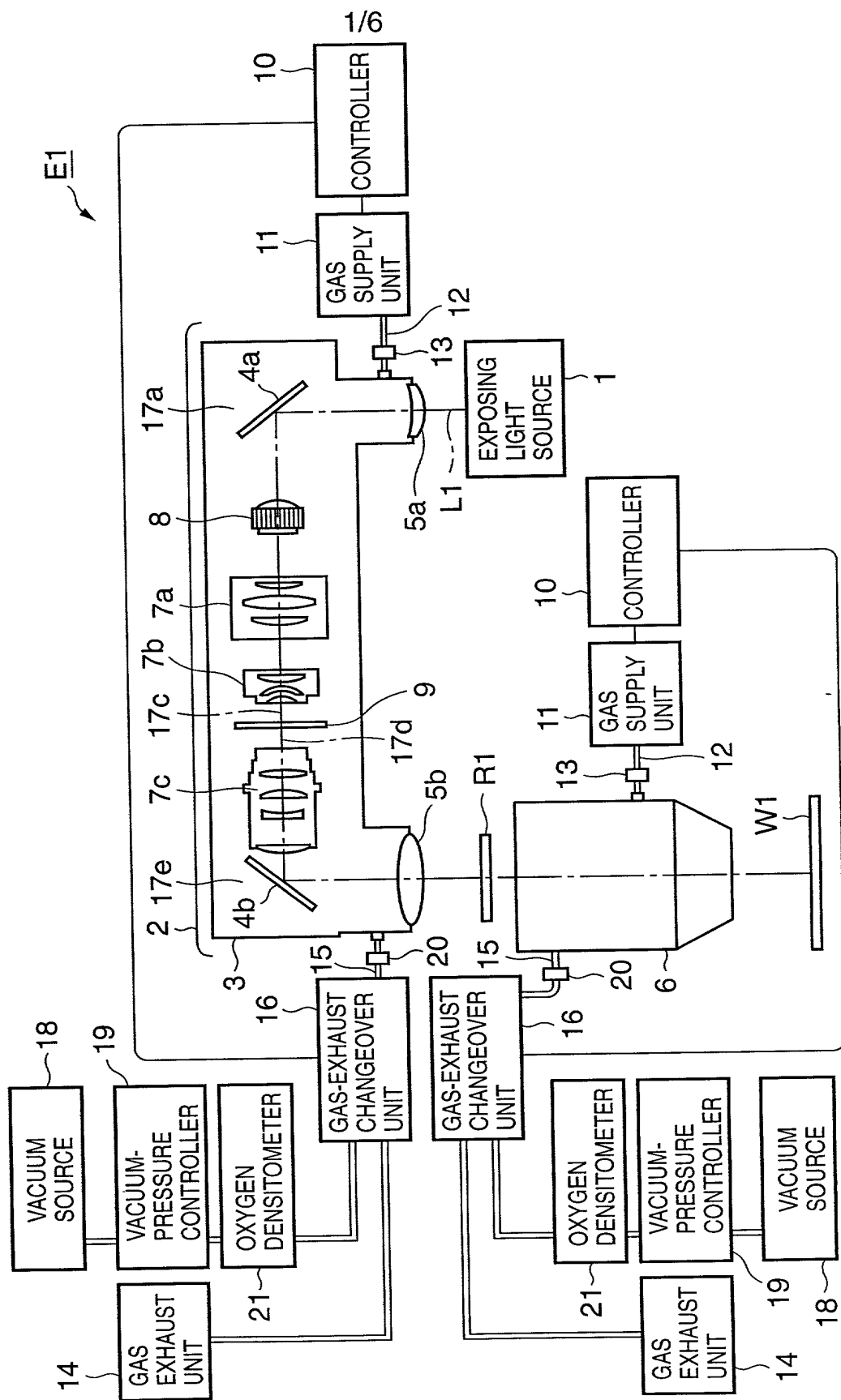


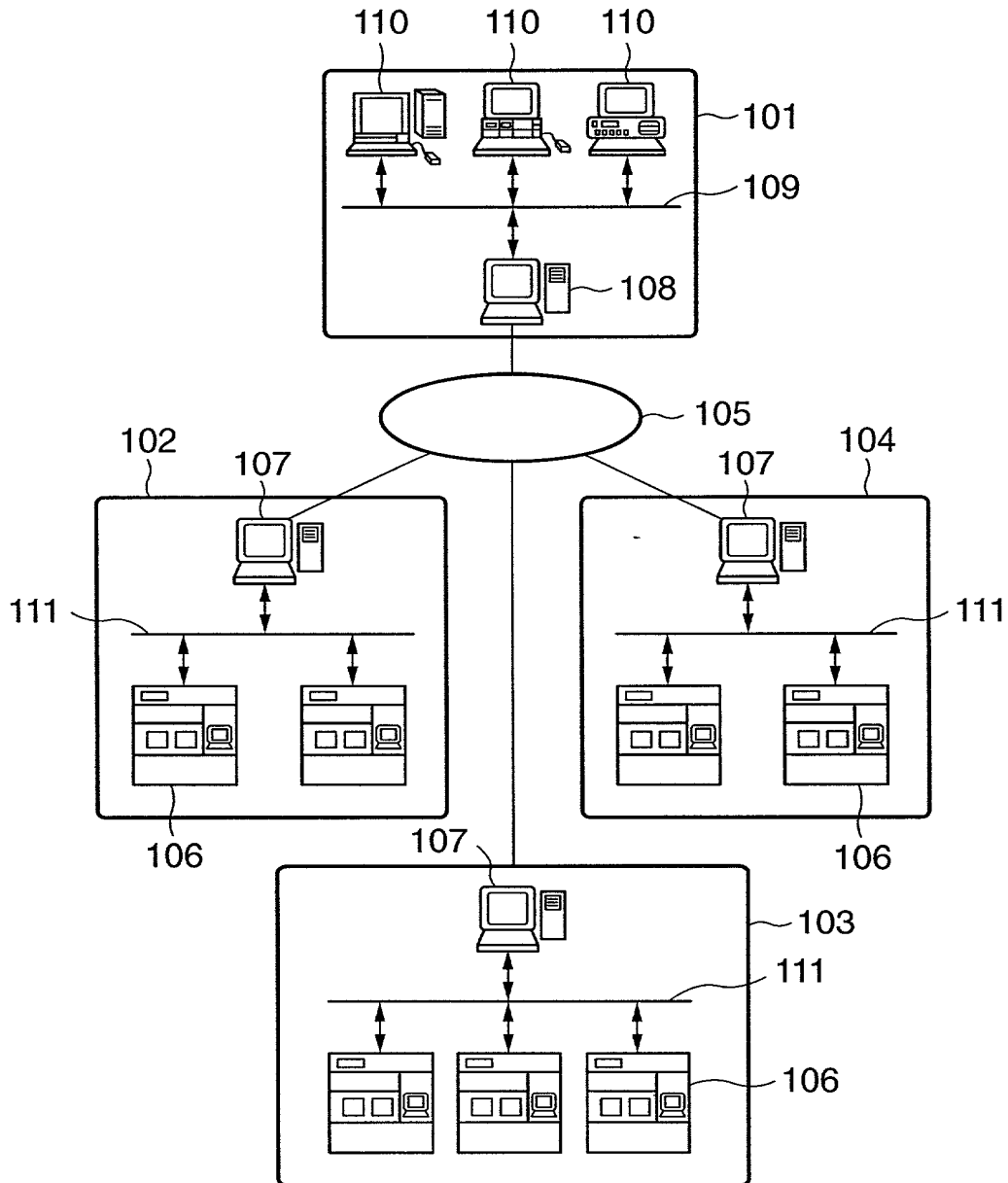
FIG. 2

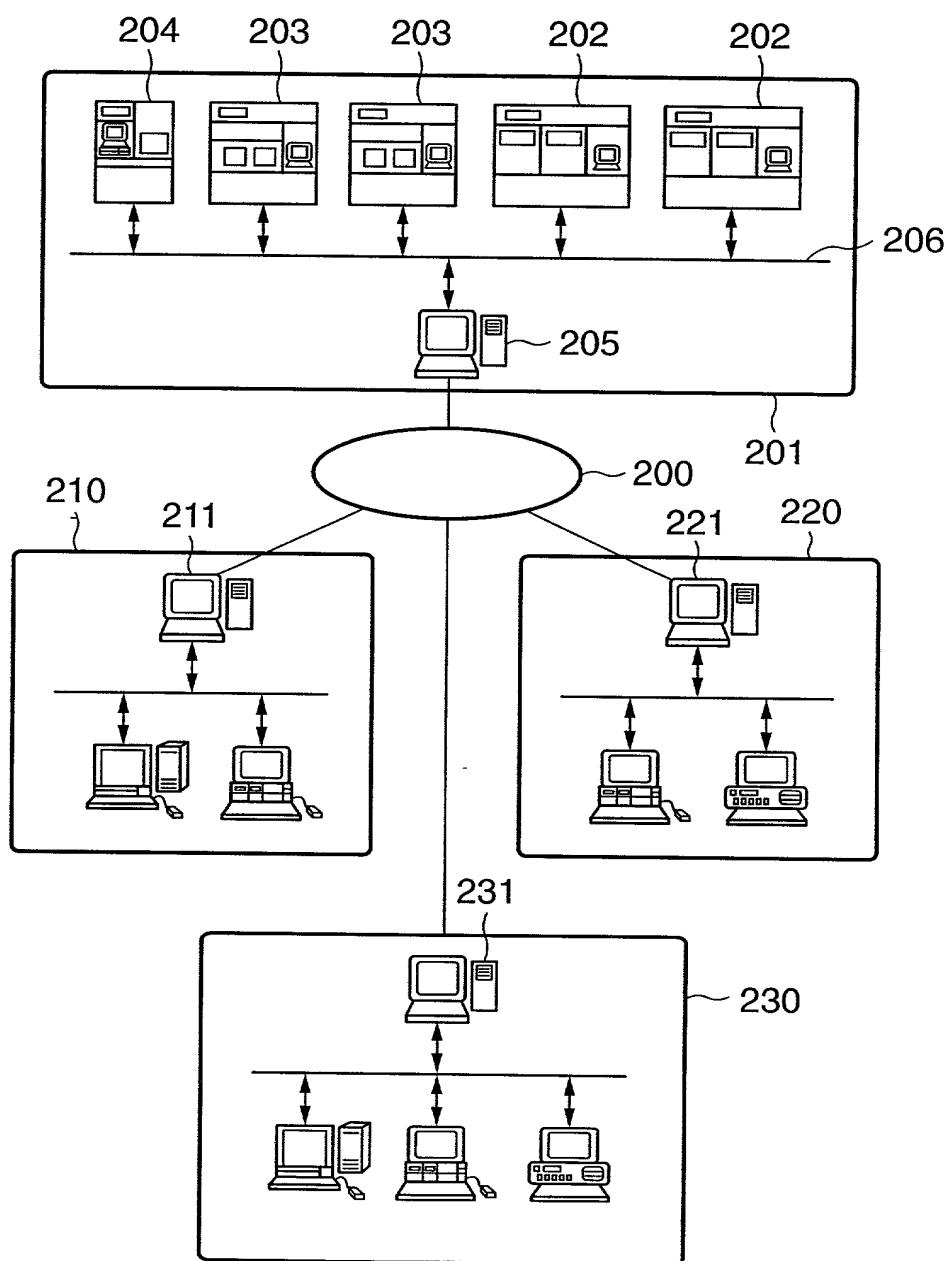
FIG. 3

FIG. 4

URL

MALFUNCTION DATABASE INPUT SCREEN

DATE OF OCCURRENCE ~ 404

MODEL ~ 401

SUBJECT MATTER ~ 403

EQUIPMENT SERIAL NO. ~ 402

DEGREE OF URGENCY ~ 405

CONDITION ~ 406

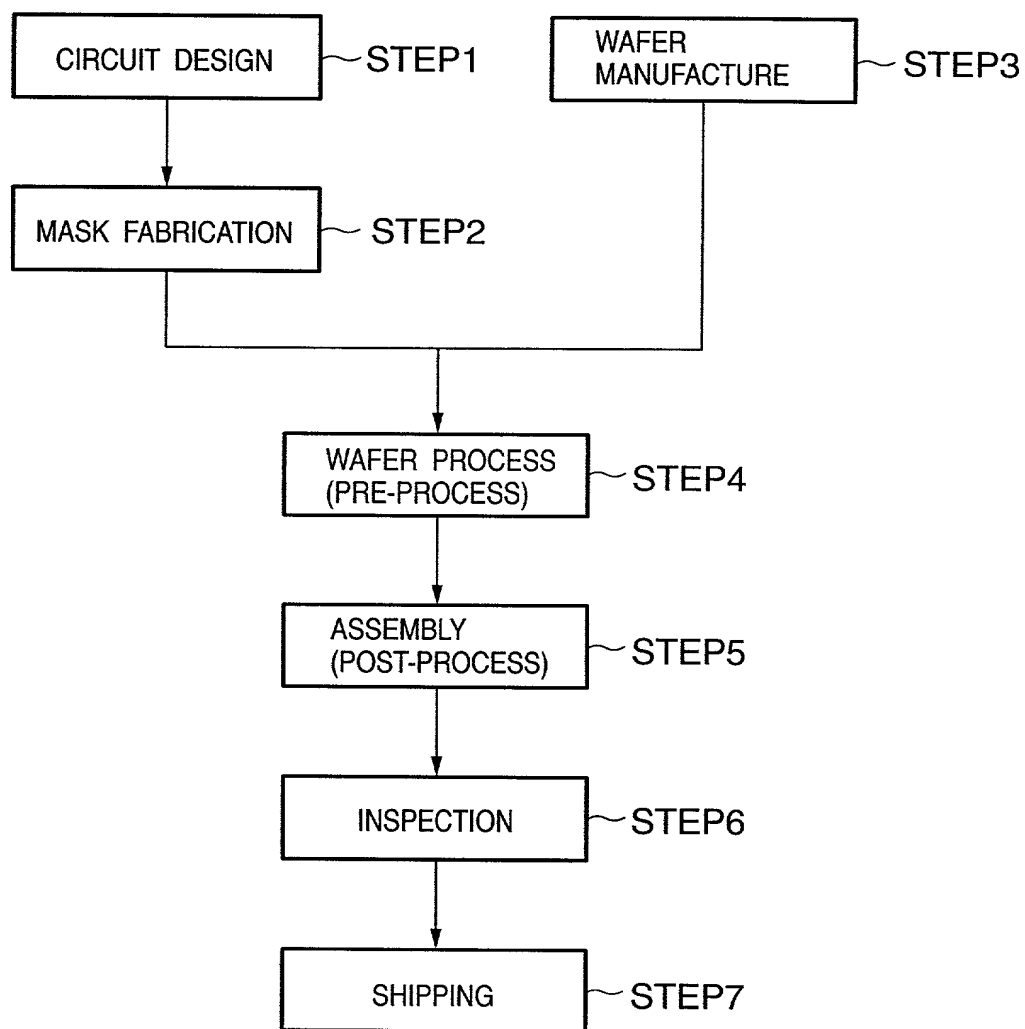
COUNTERMEASURE METHOD ~ 407

PROGRESS REPORT ~ 408

410

411

412

FIG. 5

FLOW OF SEMICONDUCTOR DEVICE MANUFACTURE

FIG. 6